

Search Notes

Application/Control No.

10/774,788

Examiner

Patrick J. Lee

Applicant(s)/Patent under
Reexamination

SHIN ET AL.

Art Unit

2878

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|---|------------|----------|
| 250 | 227.14, 227.16, 227.18, 227.23 | 11/17/2005 | PL |
| 385 | 12-13 | 11/17/2005 | PL |
| 385 | 31-32 | 11/17/2005 | PL |
| 385 | 37 | 11/17/2005 | PL |
| 356 | 32, 35.5 | 11/17/2005 | PL |
| 356 | 73.1 | 11/17/2005 | PL |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------------|----------|
| 250 | 227.18 | 11/17/2005 | PL |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|------------|------|
| Consulted w/ S. Allen | 5/17/2005 | PL |
| East (See attached) | 5/18/2005 | PL |
| East (See attached) | 5/19/2005 | PL |
| East (See attached) | 9/19/2005 | PL |
| East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT | 11/17/2005 | PL |
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